

Amendments to the Specification

In the Specification:

Please replace paragraph [0016] with the following rewritten paragraph:

[0016] FIG. 3 shows a microscope having ~~in the working position an arrangement to compensate for the image offset produced by the analyzer~~ a fluorescence device in the working position.

Please replace paragraph [0017] with the following rewritten paragraph:

[0017] FIG. 4 shows a microscope having ~~a fluorescence device in the working position in the working position an arrangement to compensate for the image offset produced by the analyzer.~~

Please replace paragraph [0018] with the following rewritten paragraph:

[0018] In FIG. 1, a polarizing filter is arranged as analyzer 1. The vibration direction that is allowed to pass is indicated schematically by a double arrow. Arranged directly behind analyzer 1 in the direction of the camera (not depicted), i.e. in the imaging direction, are a first glass wedge plate 2 and a second glass wedge plate 3. They are located one above another within a receiving ring 4, first glass wedge plate 2 and second glass wedge plate 3 being separated from one another by a spacer ring 5. Spacer ring 5 permits a rotation of first glass wedge plate 2 with respect to second glass wedge plate 3 and vice versa. Glass wedge plates 2 and 3 can in this fashion be aligned with respect to one another in such a way that the total beam deflection cumulatively generated by the two glass wedge plates 2 and 3 together exactly compensates for the beam deflection of analyzer 1. Analyzer 1 and glass wedge plates 2 and 3 are arranged on a common mount 40.